

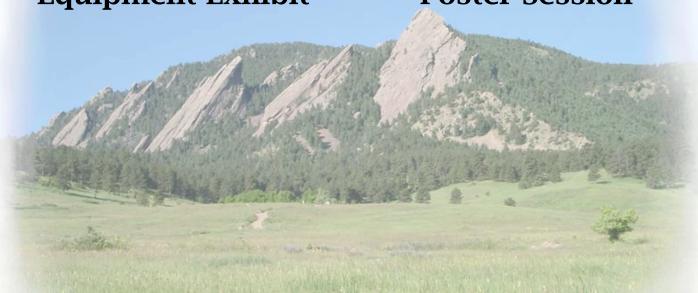


RMC-AVS 2025

ANNUAL SYMPOSIUM & EQUIPMENT EXHIBIT November 6, 2025

At the
DoubleTree by Hilton Hotel Denver-Westminster
8773 Yates Drive
Westminster, Colorado

Symposium Equipment Exhibit AVS Short Courses Poster Session



WELCOME to the 2025 Symposium of the Rocky Mountain Chapter of AVS. Thank you for joining us today!

This year's technical session presents talks on a range of topics which I hope you find interesting. I've always been excited about next generation technologies and thinking about how some new technology may drastically change how we do things, e.g., novel uses for old electric vehicle batteries, quantum computing, and the energy needs of emergent artificial intelligence technologies just to name a few.

I am pleased to welcome 20 vendors, showcasing the latest in vacuum products and services, to our 2025 Symposium. Please take a moment to visit some of these vendors and learn about the latest products in vacuum technology. Company representatives will be available to provide details about their equipment and answer questions about their products. The Vendor Exhibit is open from 10:00 a.m. to 6:00 p.m.

A highlight of our event is the Networking Hour where you will have the opportunity to attend the poster session and speak with vendors. We will have complimentary beverages and appetizers starting at 3:30 p.m. Cash awards will be presented to the top three student posters at 5:45 p.m. Door prizes will also be given away during this time (you must be present to win!). This year's oral presentations also feature a poster winner from last year's symposium – be sure to see Michael Collings' talk just before lunch.

We were pleased to offer a wide program of short courses taught by leaders in their respective fields. The slate of course topics span a wide range of vacuum technologies, system design, and troubleshooting. The chapter strives to provide in demand content at this annual symposium, and suggestions for course topics are always appreciated. We also do on-site teaching at your location when the demand is large enough.

The Rocky Mountain Chapter of the AVS is an all-volunteer organization. Thank you to the many volunteers whose efforts keep the chapter running all year long and allow us to present this annual symposium today. I would also like to thank all the symposium sponsors, attendees, exhibitors, and speakers for helping to make this symposium a success.

The Rocky Mountain AVS Chapter is always looking for volunteers to get involved in the chapter and make this symposium a successful event. If you would like to get more involved with the chapter, please contact me, or any Rocky Mountain Chapter board member. In addition, please feel free to provide any suggestions that would help us improve for the 2026 Symposium.

We hope you find the symposium stimulating, informative, and useful for your professional careers.

Steve Harvey 2025 Chair Rocky Mountain Chapter AVS

Steve.Harvey@nrel.gov

2025 Annual Symposium & Equipment Exhibit Overview

8:00 a.m. Registration begins

9:00 a.m. - 12:10 p.m. Morning Oral Session

9:00 a.m. - 12:00 p.m. A Brief Introduction to Vacuum Science and System Design

J.R. Gaines from Kurt J. Lesker Company (Private Dining Room)

10:00 a.m. Vendor Exhibit opens!

11:30 a.m. - 1:30 p.m. Free Lunch in the Exhibit Area

1:30 p.m. - 3:30 p.m. Afternoon Oral Session

3:30 p.m. - 6:00 p.m. Networking Hour: Vendor Exhibit, Student Poster Session, free

snacks, drinks, and prizes ©! (Poster authors will be present from

3:45 p.m. to 5:30 p.m. Winners announced by 5:45 p.m.)

3:45 p.m. Poster Session begins

Vendor information is posted online at https://www.rmcavs.org/vendor-exhibit/.



Contact us to see how we can help accelerate your project:

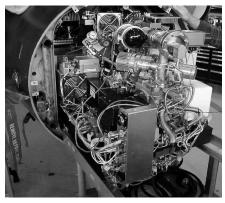
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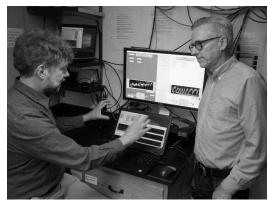
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David Thomson and Ted Anderson at CU Environmental Chambers

NOAA Single Particle Time-of-Flight Mass Spectrometer

Symposium Program

9:00 a.m. - 9:40 a.m. Advanced Manufacturing & Technology for Vacuum Web

Coating Systems

Mike Simmons, Intellivation LLC

9:40 a.m. - 10:10 a.m. Advanced Cryogenic Needs for Quantum Science (i.e., Dilution

Refrigeration)

Tim Gessert, Gessert Consulting LLC

10:10 a.m. - 10:50 a.m. Coffee Break and Vendor Exhibits

10:50 a.m. - 11:30 a.m. TBD

Cullin Wible, The Conti Group

11:30 a.m. - 12:10 p.m. Electron Enhanced Chemical Vapor Etching (EE-CVE) of β-

Ga₂O₃ with Hydrogen Chloride and Positive Sample Bias

Michael Collings, University of Colorado Boulder

12:10 p.m. - 1:30 p.m. Lunch and Vendor Exhibits

1:30 p.m. - 2:10 p.m. The Quantum Revolution: Experimenters Were Also on the

Barricades

Allan Franklin, University of Colorado Boulder

2:10 p.m. - 2:50 p.m. Lateral Thermal Atomic Layer Etching of 2D MoS₂

Janine Sempel, University of Colorado Boulder

2:50 p.m. - 3:30 p.m. Surface and Interface Characterization of Fuel Cell and

Electrolyzer Components: Challenges, Advances, Insights, and

Best Practices

Svitlana Pylypenko, Colorado School of Mines

3:30 p.m. - 6:00 p.m. Networking Hour, Vendor Exhibits, and Poster Session.

Poster Session prizes provided by MKS https://www.mks.com/.



Abstracts can be viewed at our website: https://www.rmcavs.org/2025-symposium/.

Save the date for 2026: Vendor Exhibit and Symposium on Thursday, September 17, 2026. Short courses will be offered September 16-18, 2026. Send us your suggestions or request a course on-site at your location: neil_peacock@avs.org.



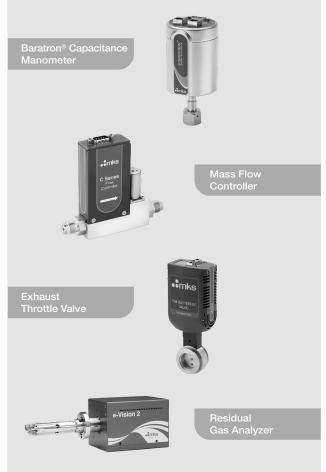
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